

FIG. 1A

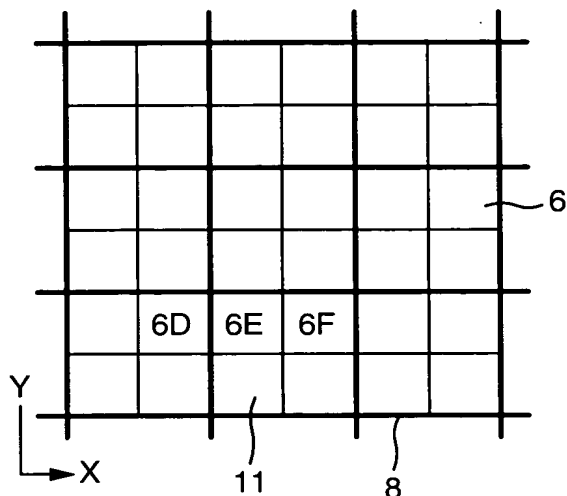


FIG. 1B

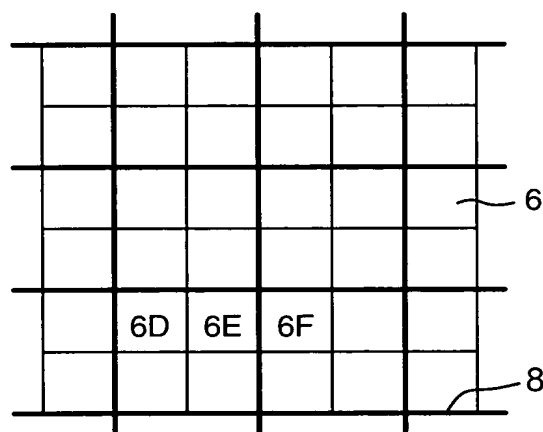


FIG. 1C

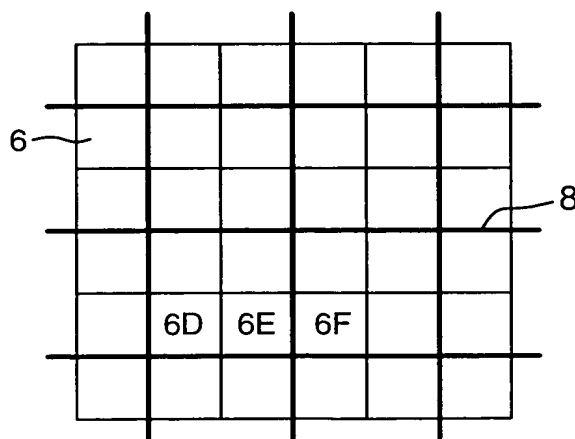


FIG. 2A

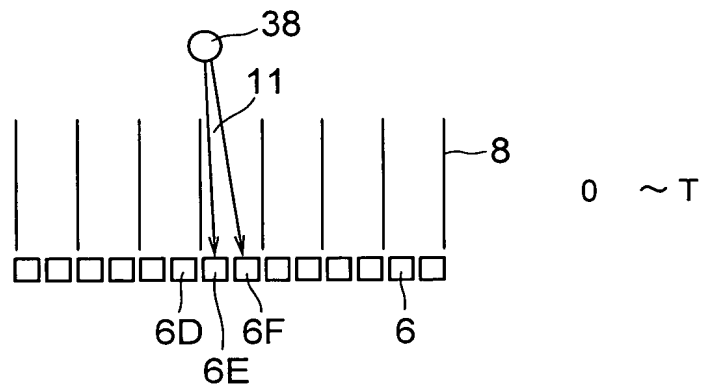


FIG. 2B

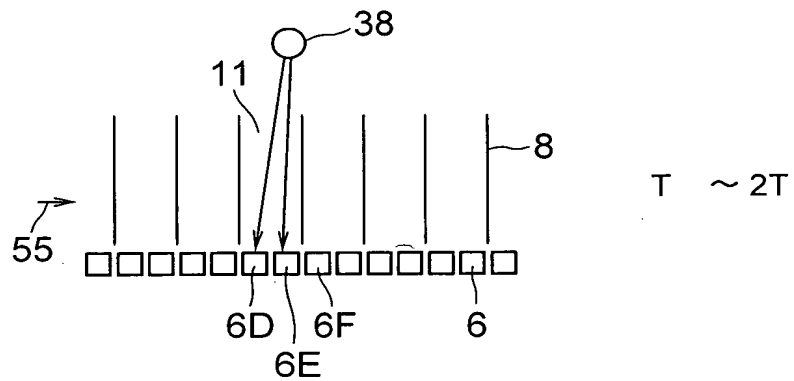
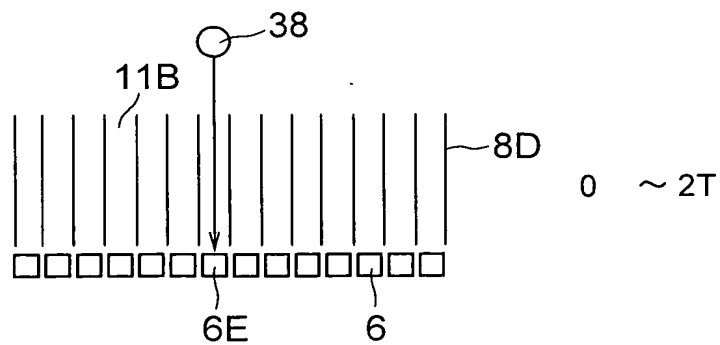


FIG. 2C



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Figure 1 is a schematic diagram of a system for measuring the thickness of a film. The system includes a sample stage (24) with a sample (26) and a film (25). A probe (33) is positioned above the sample. A measurement unit (28) is connected to the probe and a data storage unit (30). A computer (31) is also connected to the measurement unit. The diagram shows a cross-section of the sample and the probe, with various components labeled with numbers.

FIG. 5

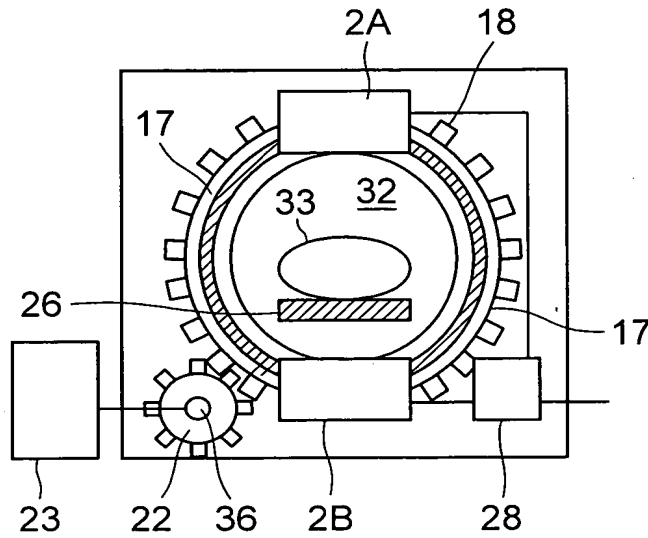


FIG. 6

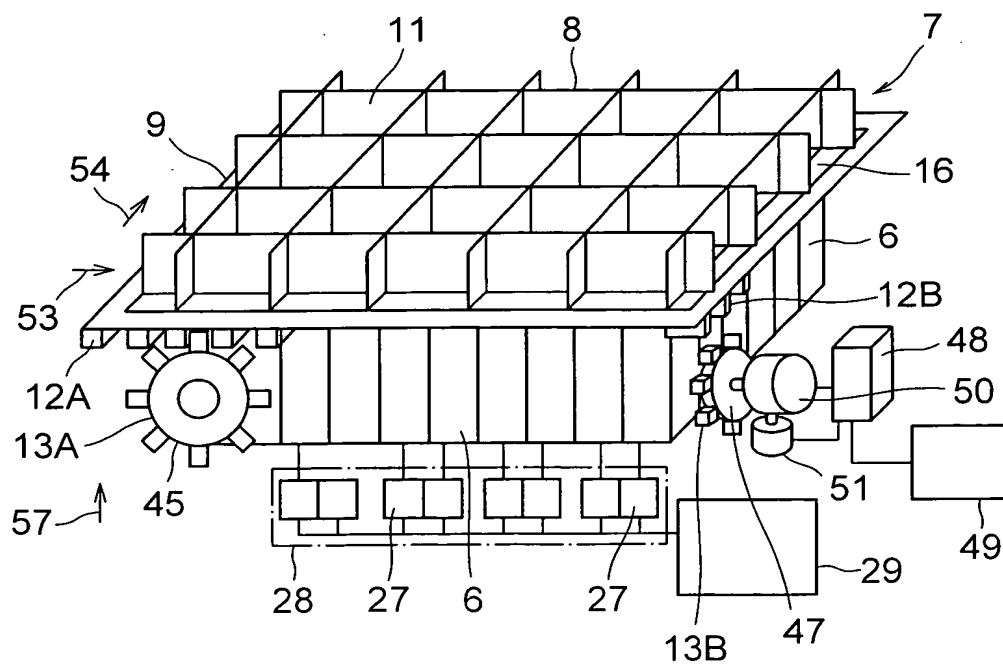


FIG. 7

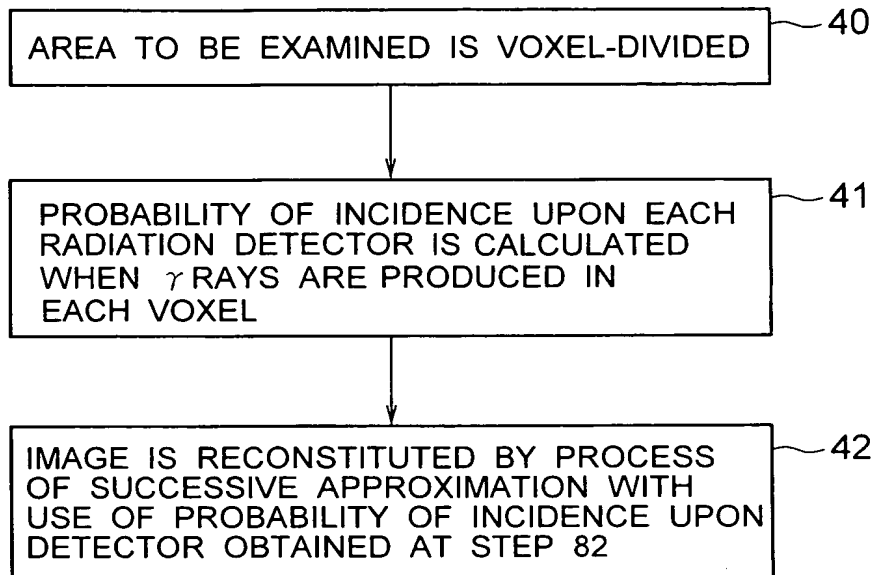


FIG. 8

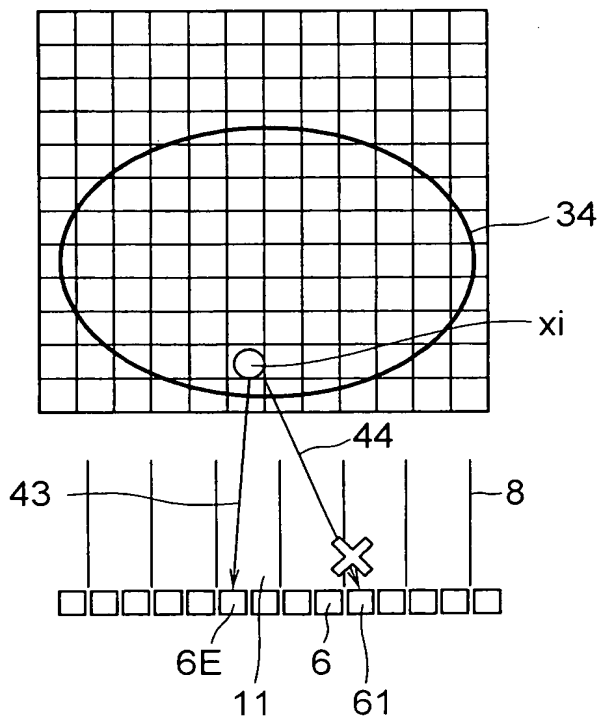


FIG. 9

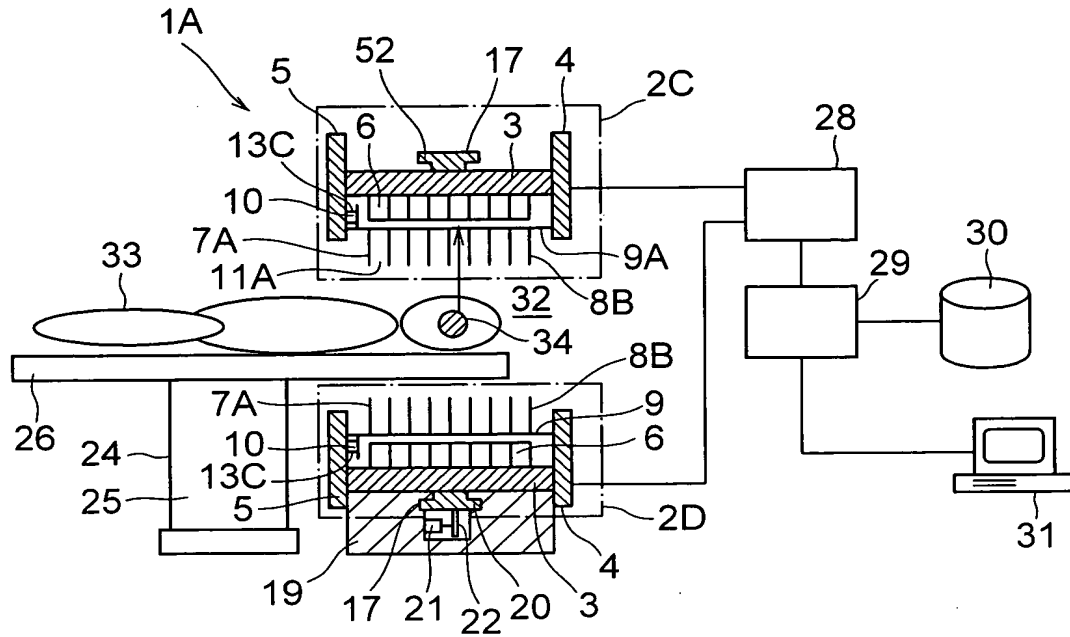


FIG. 10

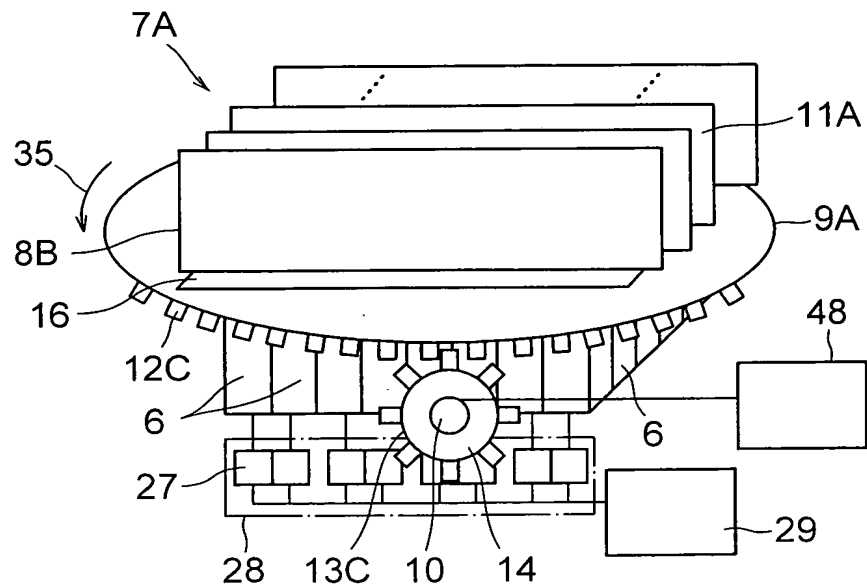


FIG. 11A

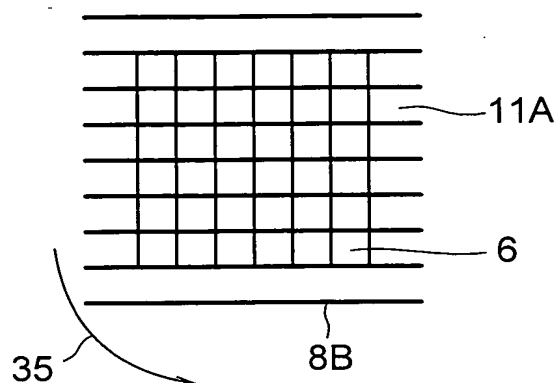


FIG. 11B

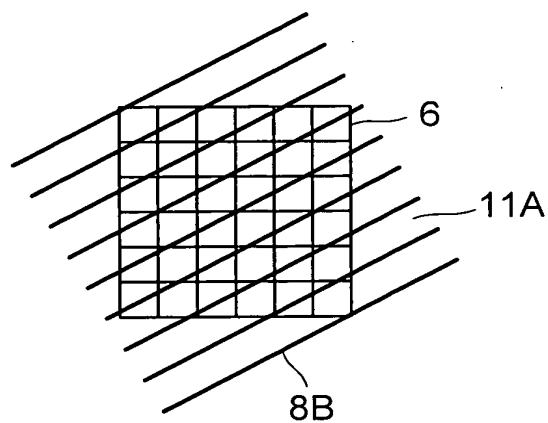


FIG. 11C

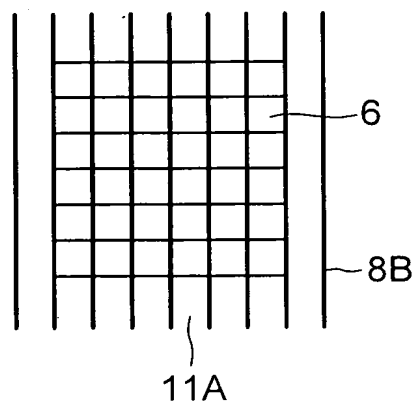
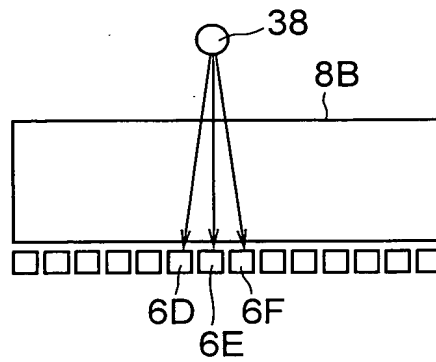
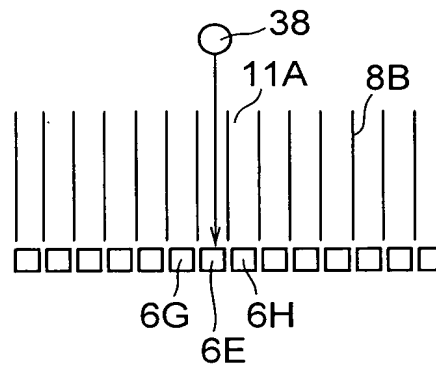


FIG. 12A



0 ~ T

FIG. 12B



T ~ 2T